



International Organization of Legal Metrology

Organisation Internationale de Métrologie Légale

OIML Update

Willem Kool

BIML Assistant Director



Overview

- Outcome of the 45th CIML meeting (Orlando, FL, USA, 20-24 September 2010)
- Cooperation with other International Organizations
- Revision of OIML D 1 – Status
- Revision the VIML – Status



45th CIML meeting





45th CIML meeting CIML Presidency

President-elect:

Mr. Peter Mason, CIML Member for the UK, Chief Executive of the NMO (UK).

New Vice-President:

Dr. Roman Schwartz, CIML Member for Germany, Head of the Division 'Mass' in PTB



45th CIML meeting

Confirmed Publications

OIML R 92 *Wood moisture meters - ...*

OIML R 127 *Radiochromic film dosimetry ...*

OIML R 131 *Polymethylmethacrylate (PMMA) dosimetry systems ...*

OIML R 132 *Alanine EPR dosimetry systems ...*

OIML R 133 *Liquid-in-glass thermometers*

All OIML publications available for download free of charge at: <http://www.oiml.org/publications/>



45th CIML meeting New Project

Revision of OIML D 29: *Guide for the application of ISO/IEC Guide 65 to assessment of measuring instrument certification bodies in legal metrology,*

to be undertaken by OIML TC 3/SC 5 following the publication of ISO 17065, superseding ISO/IEC Guide 65.



45th CIML meeting New BIML Director

The CIML appointed **Mr. Stephen Patoray**
BIML Director, from 1 January 2011.



MoU's

- Revised MoU between **ILAC, IAF and OIML** signed by the respective Presidents in Shanghai, 27th October 2010 (*Accreditation of conformity assessment in legal metrology*)
- Revision of the MoU between **OIML en IEC** (Conformity assessment and technical cooperation)
- Future MoU between **OIML and UNECE** (*Regulatory cooperation*)



New project to start in 2011:

- Measurement of grain moisture

- Calibration of instruments
- Traceability
- Verification of instruments

- Work will be coordinated with relevant ISO TC



Revision of OIML D 1

OIML D 1:2004 *Elements for a law on metrology* is under revision.

- New title: *Considerations for a law on metrology*
- Sections:
 - Rationale (Why legal metrology?)
 - Guidelines for setting up structures and for legal provisions
 - Explanations
- Adoption of revised OIML D 1 expected in 2011



Revision the VIML

OIML V 1:2000 *International vocabulary of terms in legal metrology (VIML)*

- Meeting of OIML TC 1 Terminology in September 2010 discussed the 2nd Committee Draft
- 3rd CD to be circulated shortly
- TC approval expected in 2011
- CIML adoption expected in 2012



Info

www.oiml.org

Willem.Kool@oiml.org